



1. Features of SQ4126 Series:

- Ferrite based SMD inductor with lower core loss.
- Inductance range: 0.42uH to 10.0 uH, custom values are welcomed.
- High current output chokes up to 45.0 Amp with approx. 20% roll off.
- Low profile 6.65 mm Max. height.
- 8.10 x 10.30 mm Foot Print.
- Ideal for Buck Converter, VRM & High Density Board Design.
- Operating frequency of up to 1.0MHz.
- Operating temperature range of -55° C to + 130° C. RoHS & HF compliant.
- T & R Qty's: 700pcs, 13" Reel.

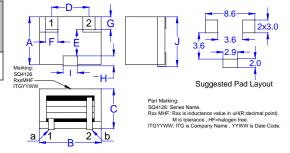


2. Electrical Characteristics of SQ4126 Series:

	OCL 1	DCR ³	DCR ³	Isat1 ⁴	Isat2 ⁴	Irms ⁵
ITG Part Number	(uH)	(mΩ)	(mΩ)	(A)	(A)	(A)
	±20%	Typical	Max.	@25°C	@125℃	@25℃
SQ4126-R42MHF	0.42	1.200	1.390	45.00	36.00	26.00
SQ4126-R56MHF	0.56	1.200	1.390	36.00	28.00	26.00
SQ4126-R68MHF	0.68	1.200	1.390	29.00	23.00	26.00
SQ4126-1R0MHF	1.00	2.200	2.800	26.00	21.00	16.00
SQ4126-1R5MHF	1.50	3.900	4.399	22.00	17.00	13.00
SQ4126-2R2MHF	2.20	6.350	6.731	18.00	14.00	11.00
SQ4126-3R3MHF	3.30	7.500	7.950	14.50	11.00	10.00
SQ4126-4R7MHF	4.70	8.600	9.169	12.00	8.90	9.40
SQ4126-5R6MHF	5.60	8.600	9.169	9.40	7.50	9.40
SQ4126-6R8MHF	6.80	8.600	9.169	7.80	6.10	9.40
SQ4126-100MHF	10.00	8.600	9.169	5.30	4.20	9.40

3. Mechanical Dimension of SQ4126 Series:

Α	В	С	D	E	F	G	Н	ı	J
Max.	Max.	Max.	Nom.	Nom.	Ref.	Nom.	Nom.	Nom.	Max.
8.10	10.30	6.65	6.00	4.20	1.80	2.30	1.30	2.40	8.20



First Angle Projection:

Notes:

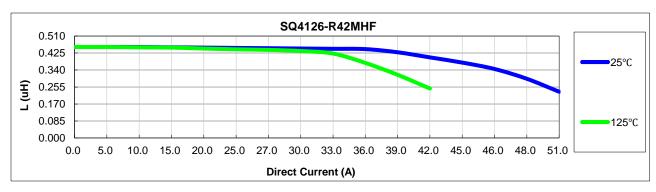
- 1. Open Circuit Inductance (OCL) test condition: 100KHz, 0.1Vrms,0Adc at 25°C.
- 2. L @ Isat and L @ Irms Test condition: 100KHz, 0.1Vrms (Ta=25°C).
- The nominal DCR is measured from point "a" to point "b", as shown above on the mechanical drawing (Ta=25°C).
- 4. Isat1, Isat2: DC current that will cause inductance to drop approximately by 20%.
- 5. Irms: DC current for an approximate temperature rise of 40°C without core loss. Derating is necessary for AC currents. PCB pad layout, trace thickness and width, air-flow and proximity of other heat generating components will affect the temperature rise.
- 6. It is recommended the part temperature not exceed 130° C under worst case operating conditions as verified in the end application.
 - New York 1 914 347 2474 Taipei 886 2 2698 8669 Kaohsiung 886 7 350 2275
- Japan 81 568 85 2830 Shenzhen 86 755 8418 6263 Shanghai 86 21 5424 5141 Hong Kong 852 9688 9767 • sales@ITG-Electronics.com • www.ITG-Electronics.com Revision D.1: March 10, 2021

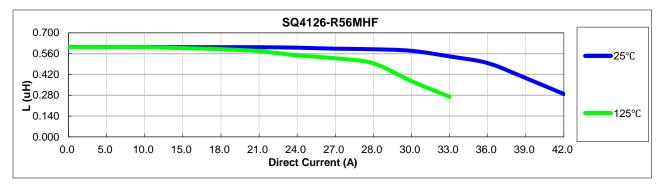


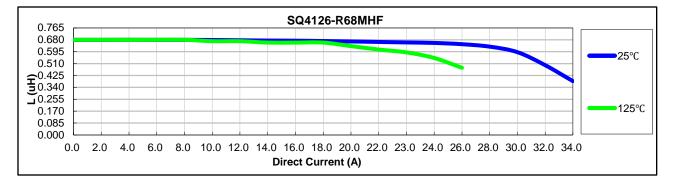


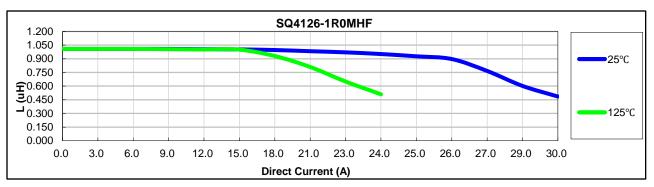


4. Inductance Characteristics of SQ4126 Series (Inductance vs Current):







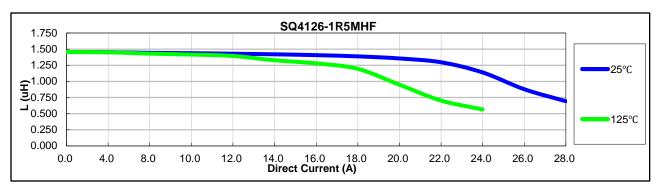


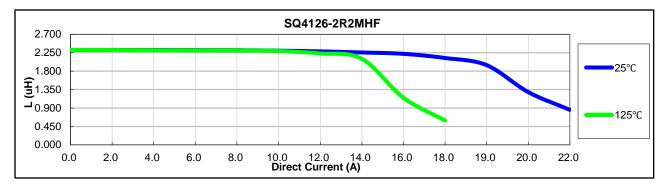
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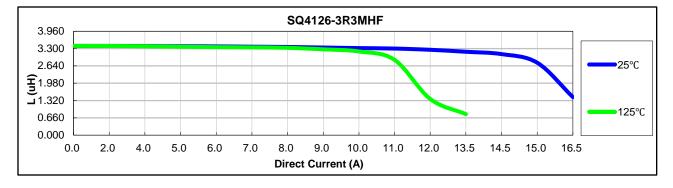


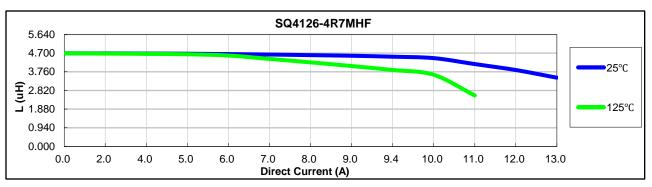


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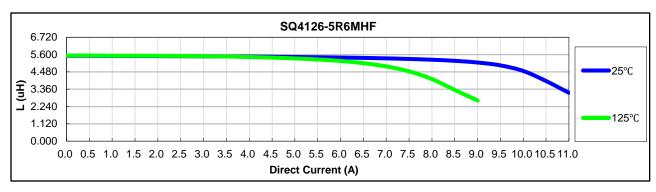


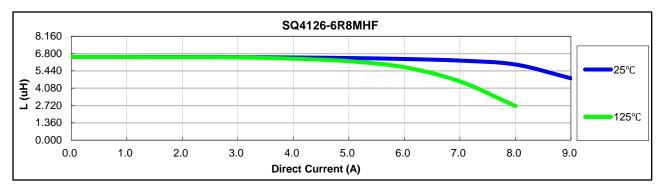
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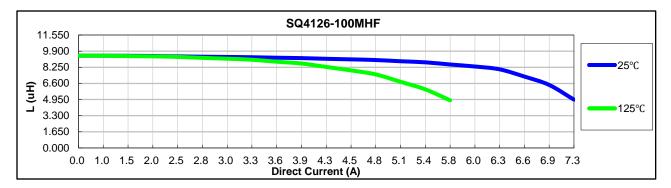




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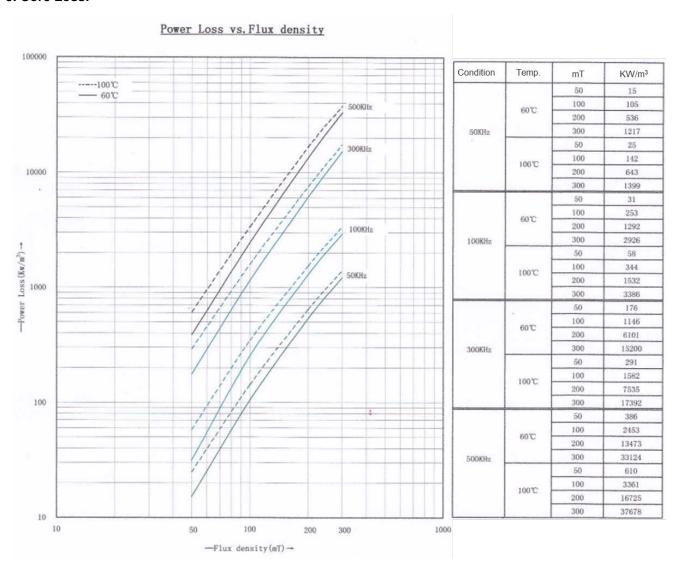








5. Core Loss:

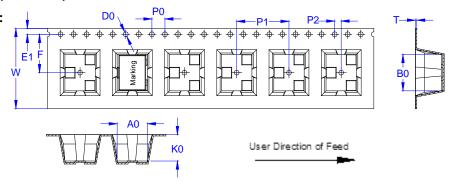






5.PACKAGE SPECIFICATION.(UNIT:mm):

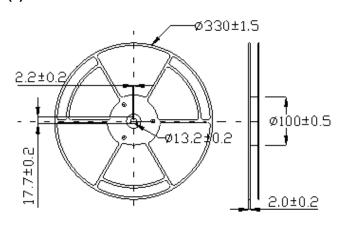
(1).ENCAPSOLATION MODE:



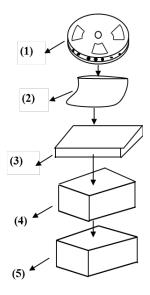
(2).DIMENSION(mm):

A0	В0	K0	P0	P1	P2	E1	F	D0	D1	W	Т
8.60±0.10	10.60±0.10	7.00±0.10	4.00±0.10	12.00±0.10	2.00±0.10	1.75±0.10	11.50±0.10	1.50+0.10-0	1.50MIN	24.00+0.30/- 0.00	0.40±0.05

(3).REEL SIZE:



(4).PACKAGE MODE:



(5).PACKAGING LIST:

No.	Packing Part	Dimension (mm)	Material	Quantity
1	Reel	330	Plastic	700Pcs/Reel
2	Bag	450 X 360 X 0.075	Plastic	1Reel/Bag
3	Small Box	340 X 335 X 45	Paper	1Bag/Small Box
4	Middle Box	356X350X226	Paper	4Small Boxes/Middle Box
5	Outer Box	378X362X252	Paper	1Middle Box/Outer Box

- (6).WEIGHT: N.W:2.00g/pcs TOTAL5.60Kg(APPROX), G.W:TOTAL11.20Kg(APPROX).
- (7).Storage conditions: -40°C~85°C,75%RH (Max.).
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*Due to continuous product improvement, all specifications are subject to change without prior notice. Kindly contact an ITG field application engineer or a sales representative prior to purchase.

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6.RELIABILITY TEST:

TEST ITEMS	SPECIFICATIONS	TEST METHOD AND REMARKS
		According to IEC68-2-20.
		1. Soldering temperature:245±5°C
Solder ability	The electrodes shall be at least 90% covered with new solder coating	2. Solder:99.3Sn/0.7Cu
	with new solder coating	3. Flux:Rosin
		4. Immersion time:5±1Sec
		1. Preheat temperature150°C.
		2. Preheat time:1min
Soldering heat	1. Appearance :no damage 2.	3. Solder temperature260±5°C
resistance	hadratan a aban manifelia I 400/ afticitial makes	4. Dipping time:10±1Sec
		Measured at room temperature after placing
		for 24hours
		According to MIL-STD-202 Method 204.
	1. Appearance:no damage	1.Frequency:10 to 55Hz.
Vibration(OUT LAB)	All Electrical and mechanical parameters within tolerance	2.Amplitude:1.52mm
	within tolerance	3.Direction and timeX Y and Z
		Direction for 2 hours each
		According to IEC68-2-3 Method Ca:
		1. Temp:40±2°C
	Appearance: no damage All Electrical and mechanical parameters	2. Humidity:90%-95%RH
Humidity resistance test	20.2 4.1	3. Test time:500 \pm 2H
		4. The component should be stabilized at
		normal condition for24 Hours before test
		According to IEC68-2-2.
		1. 1. Temperature:85±3°C
High temperature resistance test	All Electrical and mechanical parameters	2. Test time:500+24H
resistance test	within toloroppo	3. The component should be stabilized at
		normal condition for 24hours before test
		According to IEC68-2-1 Method A(Ad).
	Appearance: no damage	1. Temperature:-40±3°C
Low Temperature	1. Appearance, no damage	2. Test time:500+24H
resistance test	within tolerance	3. The component should be stabilized at
		normal condition for 24hours before test
Temperature cycles test		According to IEC68-2-14 Method N(Nb).
		1. High-temp:85±3duration:30min
	Appearance: no damage All Electrical and mechanical parameters within tolerance	2. room –temp:25±2°CDuration3H
		3. Low-temp:-40±3Duration30min
		4. room-temp: 25±2°CDuration3H
		5. Number of cycle:10cycles
		6. The component should be stabilized at
		normal condition for 24hours before test

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Soldering Reflow Chart

Stage	Precaution	Recommended temperature profile
Reflow	Temperature profile can be referenced after confirming of adhesion , temperature of resistance to soldering heat , component size , soldering etc. sufficient . Note: please refer to the latest IPC/JEDEC J-STD-020: "Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices"	Temperature *C 260 250 220 Natural cooling 60s to 90s 150s to 210s 240s to 480s